# Development of a Spot Matching Module in Image Analysis System DDGEL for 2D Gel Electrophoresis

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### Abstract

We have been developing an image analysis system named DDGEL for 2D gel electrophoresis of genomic DNA. Recently, we have developed a program module for finding a correspondence of spots between two gel electrophoresis images.

## 1 Introduction

Although hybridization-based methods and PCR-based methods have been successfully applied to analysis of genomic DNA, these methods are not suited for rapid analysis of the entire genomic DNA. Recently, a method called RLGS (Restriction Landmark Genomic Scanning) has been developed in order to detect and analyze the genetic alterations by observing the entire genomic DNA after separating DNA fragments in a single two-dimensional slab gel [1]. To analyze gel images obtained by the RLGS method, a lot of tasks must be done: thousands of spots must be detected where each spot corresponds to a gene; a correspondence of spots between two images must be detected; links between spots and genetic information must be classified and stored in a database. We have been developing a software tool named **DDGEL** so that such tasks can be done automatically or semi-automatically [2]. In this short abstract, we give a brief description about a recently developed pattern matching program for detecting a correspondence of spots between two images.

## 2 Method and Result

Spots are detected using standard image processing techniques. For two sets A and B of spots, we find a correspondence of spots between two sets by the following procedure.

- (1) A few pairs of matching spots (*landmarks*) are detected (manually or automatically).
- (2) In order to adjust distorsion, B is transformed using a matrix derived by applying the least squares fitting method to landmarks.
- (3) A is divided into several rectangular regions.
- (4) For each rectangular region, a correspondence between spots in this region and spots in B is computed using bipartite graph matching. Moreover, this correspondence is refined via iterative improvement using least squares fitting and bipartite graph matching.
- (5) A correspondence between the entire regions is refined using bipartite graph matching.

An example of a result of spot matching applied to Human DNA is shown in Figure 1. For images with  $\approx 1,150$  spots, matching was obtained in 12 seconds using SUN Ultra-2 workstation (300MHz). Even for a case that distortion between two images was not small, there was a little difference between the matching detected by the system and that detected by a human expert.



Figure 1: Example of spot matching, where parts of images are shown here. Matched spots are listed in the middle window and unmatched spots are highlighted with green edges.

## 3 Conclusion

Owing to the development of the spot matching module, DDGEL system has become a powerful tool for 2D gel image analysis. DDGEL system runs on a Unix workstation with SunOS 4.1.2, Solaris 2.3, or an upper-compatible operating system, and program codes with annotated standard gel data of Human DNA are now available via FTP (see http://www.hgc.ims.u-tokyo.ac.jp).

## References

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- [2] Ohyama, A., Akutsu, T. and Fujiyama, A., "A Software Tool for Mapping Human Genome by Chromosome-specific Two- Dimensional Electrophoresis Method," Proc. Genome Informatics Workshop 1995, pp. 144-145, 1995.